

TESCAN VEGA3 VP-SEM

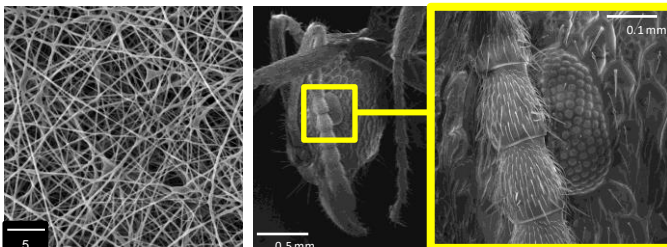
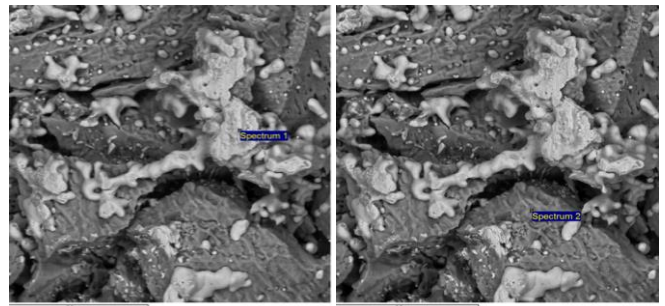
The Vega is a Variable Pressure Scanning Electron Microscope (VP-SEM) with a tungsten filament. It is suitable for lower magnification microstructural analysis at high vacuum, or for the analysis of uncoated and/or hydrated samples at low vacuum, with a smallest particle size of approximately one micrometre.

Key Capabilities

- Secondary Electron (SE) imaging
- Backscattered Electron (BSE) imaging
- Low vacuum imaging of non-conductive, porous and/or moist samples
- Energy Dispersive X-ray Spectroscopy (EDS) point analysis, line scanning and elemental mapping

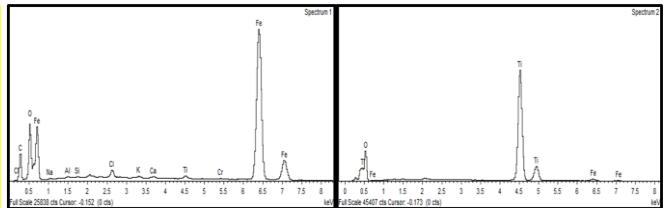
Application Examples

- Investigation of corrosion products
- Identification and characterisation of asbestos fibres and building materials
- Measurement of discrete layers in composite materials
- Imaging of bacteria and muscle tissue
- Non-destructive analysis of samples that cannot be prepared for high vacuum



Electrospun polymer fibres (pHEMA) forming a mat for microalgae immobilisation

An ant's head, with a close-up showing the structure of its eye and antenna



The above spectra show the elemental compositions of the two different materials that constitute the sample shown above. The brighter areas in the BSE image are iron-rich and the darker areas are titanium-rich.

For more information

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